Atomic Force Microscopy Analysis

Atomic Force Microscopy (AFM) provides images with near-atomic resolution to study the surface structure of solid materials including insulators. It is mainly used to measure the surface morphology, conductivity, surface potential, electric field, magnetic domain, friction, viscoelasticity, adhesion, I/V curve, modulus, dopant distribution and other surface properties of substances.

STEMart conducts atomic force microscopy analysis to measure surface topography of various materials, including polymers, ceramics, composites, glass, and biological samples.

Test Capabilities

- Surface properties measurement
- Hardness and modulus measurement
- AFM measurements for characterizations of surface treatment effects
- Surface observation
- Size determination
- Surface roughness measurement
- Granularity analysis
- Statistical processing of bumps and pits
- Evaluation of film forming conditions
- Measurement of the size step of the protective layer

- Evaluation of flatness of interlayer insulation film
- VCD coating evaluation
- Evaluation of the rubbing treatment process of oriented film
- Defect analysis

For more information about our atomic force microscopy analysis services, please contact us.